

## BYPASSING A DEVICE IN A SCAN CHAIN

### ABSTRACT OF THE INVENTION

Methods and systems for testing devices in a scan chain are described.

- 5 A first device for test and a second device for test are coupled in the scan chain. A signal selector is coupled between the first and second devices. The signal selector selects between an output signal that is output from the first device and a bypass signal that has bypassed the first device.